

WHAT IS CLAIMED IS:

- 1 1. An apparatus comprising:
 - 2 a charge pump having a capacity that is preset to a
 - 3 particular value; and
 - 4 a measuring circuit to measure an actual capacity of the
 - 5 charge pump and to reset the capacity of the charge pump to a
 - 6 value based on the measured capacity.
- 1 2. The apparatus of claim 1 wherein an output of the charge
- 2 pump is preset to operate at particular voltage and current
- 3 levels.
- 1 3. The apparatus of claim 1 wherein the measuring circuit
- 2 includes a temperature sensor.
- 1 4. The apparatus of claim 1 wherein the measuring circuit
- 2 includes a voltage sensor to sense a voltage at an input of
- 3 the charge pump.
- 1 5. The apparatus of claim 1 wherein the measuring circuit
- 2 includes a voltage sensor to sense a voltage at an output of
- 3 the charge pump.
- 1 6. The apparatus of claim 1 wherein the measuring circuit
- 2 includes a current sensor to sense a current at an output of
- 3 the charge pump.

1 7. An apparatus comprising:

2 an array of memory cells; and

3 a charge pump circuit coupled to the array of memory

4 cells to drive the array of memory cells, the charge pump

5 circuit comprising:

6 a charge pump having a capacity that is preset to a

7 particular value, and

8 a measuring circuit to measure an actual capacity of

9 the charge pump and to reset the capacity of the charge

10 pump to a value based on the measured capacity.

1 8. The apparatus of claim 7 wherein an output of the charge

2 pump is preset to operate at particular voltage and current

3 levels.

1 9. The apparatus of claim 7 wherein the measuring circuit

2 includes a temperature sensor.

1 10. The apparatus of claim 7 wherein the measuring circuit

2 includes a voltage sensor to sense a voltage at an input of

3 the charge pump.

1 11. The apparatus of claim 7 wherein the measuring circuit

2 includes a voltage sensor to sense the voltage at an output of

3 the charge pump.

1 12. The apparatus of claim 7 wherein the measuring circuit
2 includes a current sensor to sense a current at an output of
3 the charge pump.

1 13. A computer system comprising:
2 a central processor; and
3 a memory coupled to the central processor, the memory
4 comprising:

5 an array of memory cells, and
6 a charge pump circuit coupled to the array of memory
7 cells to drive the array of memory cells, the charge pump
8 circuit comprising:
9 a charge pump having a capacity that is preset to a
10 particular value, and
11 a measuring circuit to measure an actual capacity of
12 the charge pump and to reset the capacity of the charge
13 pump to a value based on the measured capacity.

1 14. The computer system of claim 13 wherein an output of the
2 charge pump is preset to operate at particular voltage and
3 current levels.

1 15. The computer system of claim 13 wherein the measuring
2 circuit includes a temperature sensor.

1 16. The computer system of claim 13 wherein the measuring
2 circuit includes a voltage sensor to sense a voltage at an
3 input of the charge pump.

1 17. The computer system of claim 13 wherein the measuring
2 circuit includes a voltage sensor to sense a voltage at an
3 output of the charge pump.

1 18. The computer system of claim 13 wherein the measuring
2 circuit includes a current sensor to sense the current at an
3 input of the charge pump.

19. A method comprising:

 measuring a capacity of a charge pump; and
 resetting the capacity of the charge pump to a value
 based on the measured capacity.

1 20. The method of claim 19 further comprising presetting a
2 capacity of the charge pump to a particular value.

3 21. The method of claim 20 wherein presetting a capacity of
4 the charge pump to a particular value includes presetting the
5 charge pump to particular voltage and current levels.

1 22. The method of claim 19 wherein measuring the capacity of
2 the charge pump includes measuring a temperature of the charge
3 pump.

1 23. The method of claim 19 wherein measuring the capacity of
2 the charge pump includes measuring a voltage at an input of
3 the charge pump.

1 24. The method of claim 19 wherein measuring the capacity of
2 the charge pump includes measuring a voltage at an output of
3 the charge pump.

1 25. The method of claim 19 wherein measuring the capacity of
2 the charge pump includes measuring a current at an output of
3 the charge pump.